




<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10603055	BLASI ET AL.
	Examiner Jacob, Mary C	Art Unit 2123

Notes	Date	Examiner
Inventor Name Search: PALM, Google Scholar, IEEE	06/01/2006	MCJ
Assignee Name Search: EAST, Google Scholar	06/01/2006	MCJ
702/117,123; 703/15 (see search history)	06/01/2006	MCJ
EAST Search: (see search history) ( ( 'test bench'<in>metadata ) <and> ( generate<in>metadata ) )<and> ( hdl <or> 'hardware description language'<in>metadata )		
IEEE, ACM: test bench, generate, hardware description language, Virtual Intellectual Property Library	6/5/06	MCJ
Google Scholar: Virtual Intellectual Property Library	6/5/06	MCJ
U.S. Patent and Trademark Office		Part of Paper No.:

<p><b>Searched</b></p> 	Application/Control No. 10603055	Applicant(s)/Patent Under Reexamination BLASI ET AL.
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Class	SubClass	Date	Examiner
703	15	6/6/06	MCJ

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<b><i>Interference Searched</i></b>  	Application/Control No.  10603055	Applicant(s)/Patent Under Reexamination  BLASI ET AL.
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